Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination		
10/774,883	FUNG ET AL.		
Examiner	Art Unit		
Phallaka Kik	2825		

SEARCHED					
Class	Subclass	Date	Examiner		
716	6,9,10,16, 18	2/3/2006	PK		
716	16,18	2/7/2006	PK		
Above	updated	5/27/2006	PK		
Above	updated	8/21/2006	PK		
Above	updated	12/6/2006	PK		

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
716	6,9,10,16	12/7/2006	PK		
716	18	12/7/2006	PK		
-USPGPUB (see attached)		12/7/2006	PK		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
BRS (EAST)USPAT, USPGPUB Class/sub searched: 716/1-18 (see attached)	2/3/2006	PK		
Above updated (see attached)	5/27/2006	PK		
Above updated (see attached)	8/21/2006	PK		
Above updated (see attached)	12/6/2006	PK		
EPO, JPO, IBM TDB, Derwent (see attached)	2/3/2006	PK		
IEE/IEEE Xplore (see attached)	2/3/2006	PK		